Searcn Notes					

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/768,667	SCHUHRKE ET AL.	
Examiner	Art Unit	
Madeleine AV Nguyen	2625	

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		504				
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38	32	167				
		162				
38	32	165	3/16/	/2008	A	V

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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